

TOSHIBA Field Effect Transistor Silicon P-Channel MOS Type

SSM3J111TU

High Speed Switching Applications

- 2.5V drive
- Low on-resistance: $R_{on} = 480\text{m}\Omega$ (max) (@ $V_{GS} = -4\text{ V}$)
 $R_{on} = 680\text{m}\Omega$ (max) (@ $V_{GS} = -2.5\text{ V}$)
- Lead(Pb)-free

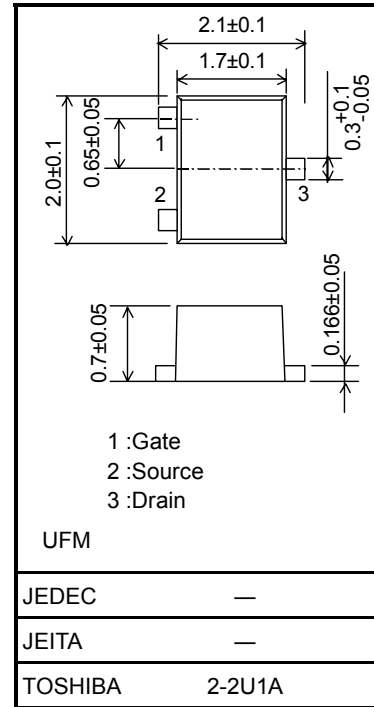
Maximum Ratings ($T_a = 25^\circ\text{C}$)

Characteristic	Symbol	Rating	Unit
Drain-Source voltage	V_{DS}	-20	V
Gate-Source voltage	V_{GSS}	± 12	V
Drain current	DC	I_D	A
	Pulse	I_{DP}	
Drain power dissipation	P_D (Note1)	800	mW
	P_D (Note2)	500	
Channel temperature	T_{ch}	150	$^\circ\text{C}$
Storage temperature range	T_{stg}	-55~150	$^\circ\text{C}$

Note1: Mounted on ceramic board.
 (25.4 mm × 25.4 mm × 0.8 mm, Cu Pad: 645 mm²)

Note2: Mounted on FR4 board.
 (25.4 mm × 25.4 mm × 1.6 mm, Cu Pad: 645 mm²)

Unit: mm



Weight: 6.6 mg (typ.)

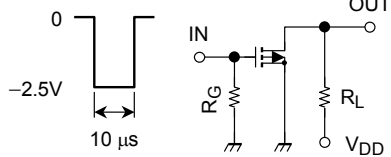
Electrical Characteristics ($T_a = 25^\circ\text{C}$)

Characteristic	Symbol	Test Conditions	Min	Typ.	Max	Unit
Drain-Source breakdown voltage	$V_{(BR)DSS}$	$I_D = -1\text{ mA}$, $V_{GS} = 0$	-20	—	—	V
Drain cut-off current	I_{DSS}	$V_{DS} = -20\text{ V}$, $V_{GS} = 0$	—	—	-1	μA
Gate leakage current	I_{GSS}	$V_{GS} = \pm 12\text{ V}$, $V_{DS} = 0$	—	—	± 1	μA
Gate threshold voltage	V_{th}	$V_{DS} = -3\text{ V}$, $I_D = -0.1\text{ mA}$	-0.6	—	-1.1	V
Forward transfer admittance	$ Y_{fs} $	$V_{DS} = -3\text{ V}$, $I_D = -0.3\text{ A}$ (Note3)	0.6	1.2	—	S
Drain-Source on-resistance	$R_{DS(ON)}$	$I_D = -0.3\text{ A}$, $V_{GS} = -4.0\text{ V}$ (Note3)	—	380	480	m Ω
		$I_D = -0.3\text{ A}$, $V_{GS} = -2.5\text{ V}$ (Note3)	—	530	680	
Input capacitance	C_{iss}	$V_{DS} = -10\text{ V}$, $V_{GS} = 0$, $f = 1\text{ MHz}$	—	160	—	pF
Output capacitance	C_{oss}	$V_{DS} = -10\text{ V}$, $V_{GS} = 0$, $f = 1\text{ MHz}$	—	90	—	pF
Reverse transfer capacitance	C_{rss}	$V_{DS} = -10\text{ V}$, $V_{GS} = 0$, $f = 1\text{ MHz}$	—	25	—	pF
Switching time	Turn-on time	$V_{DD} = -10\text{ V}$, $I_D = -0.3\text{ A}$, $V_{GS} = 0 \sim -2.5\text{ V}$, $R_G = 4.7\text{ }\Omega$	—	27	—	ns
	Turn-off time		—	43	—	
Drain-Source forward voltage	V_{DSF}	$I_D = 1\text{ A}$, $V_{GS} = 0\text{ V}$ (Note3)	—	0.85	1.2	V

Note3: Pulse test

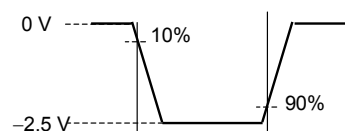
Switching Time Test Circuit

(a) Test circuit

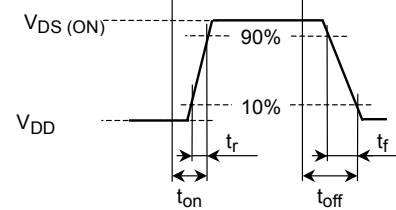


$V_{DD} = -10\text{ V}$
 $R_G = 4.7\ \Omega$
 $D.U. \leq 1\%$
 V_{IN} : $t_r, t_f < 5\text{ ns}$
 Common Source
 $T_a = 25^\circ\text{C}$

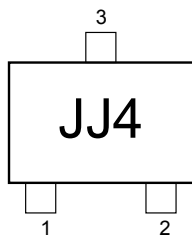
(b) V_{IN}



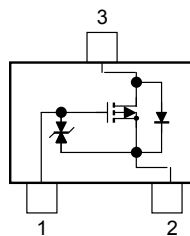
(c) V_{OUT}



Marking



Equivalent Circuit (top view)



Precaution

V_{th} can be expressed as the voltage between gate and source when the low operating current value is $I_D = -0.1\text{ mA}$ for this product. For normal switching operation, $V_{GS(ON)}$ requires a higher voltage than V_{th} , and $V_{GS(OFF)}$ requires a lower voltage than V_{th} .

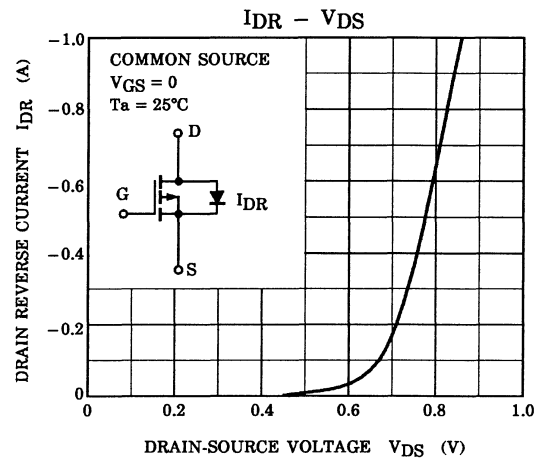
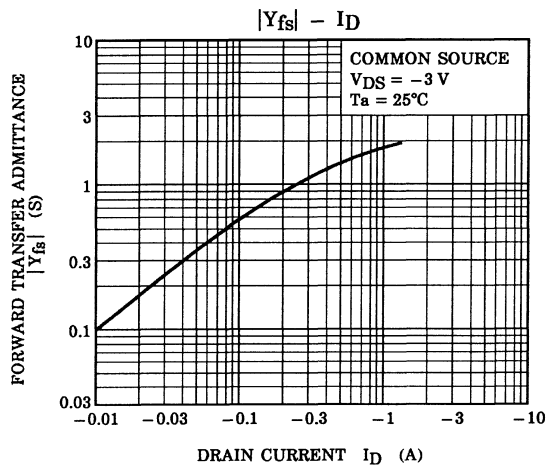
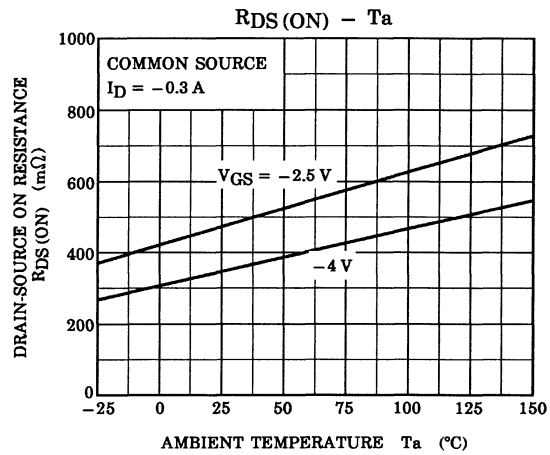
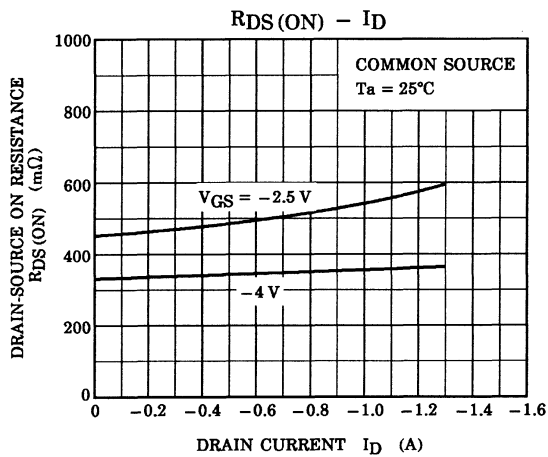
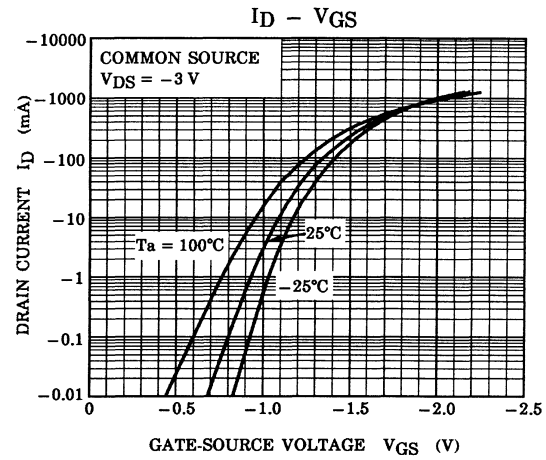
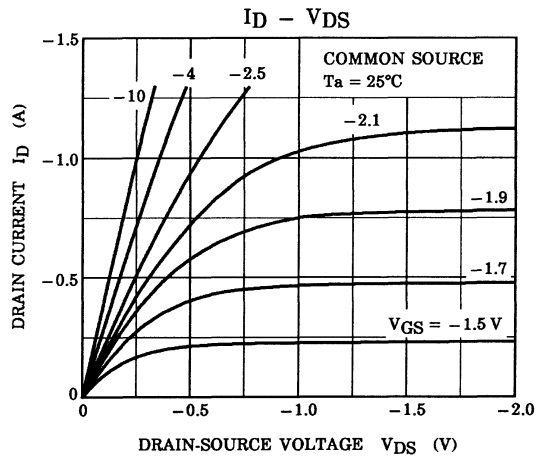
(The relationship can be established as follows: $V_{GS(OFF)} < V_{th} < V_{GS(ON)}$)

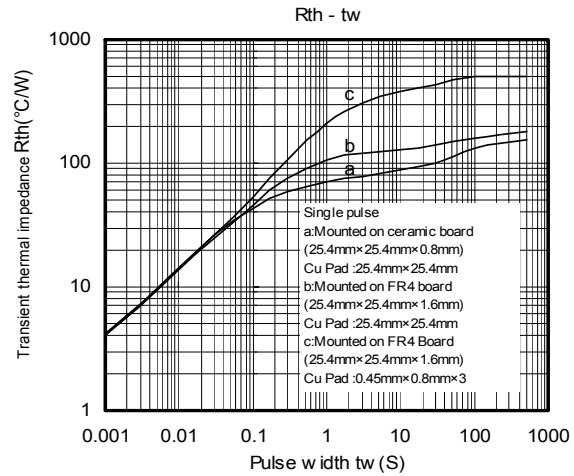
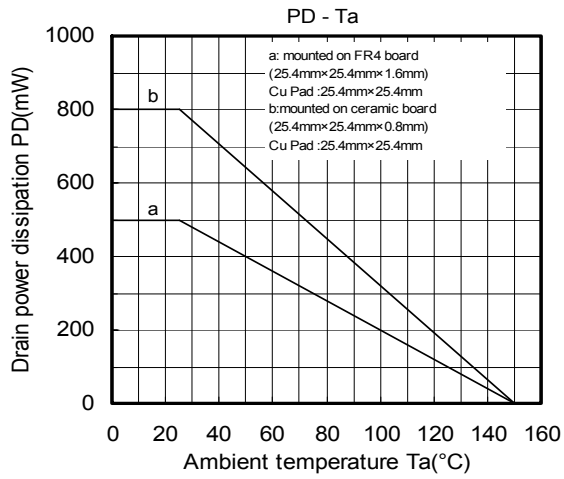
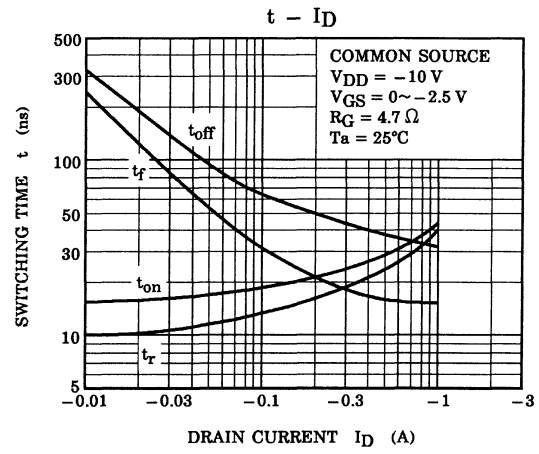
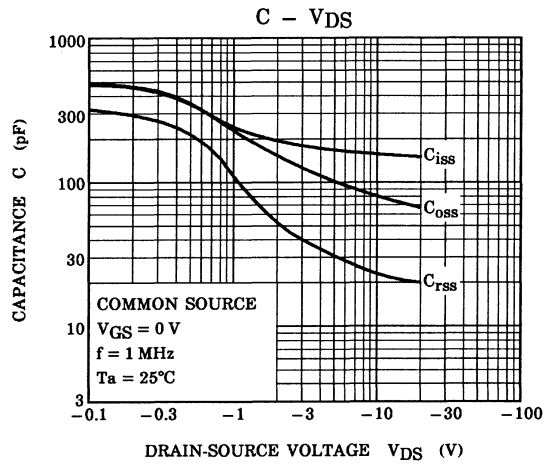
Take this into consideration when using the device.

The recommended V_{GS} voltage for turning on this product is -2.5 V or higher.

Handling Precaution

When handling individual devices which are not yet mounted on a circuit board, be sure that the environment is protected against electrostatic discharge. Operators should wear anti-static clothing, and containers and other objects that come into direct contact with devices should be made of anti-static materials.





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